

Silicon Nitride NEMS at Low Temperatures: Mechanical and Thermal Properties

NPCQS 2012, 24th of April

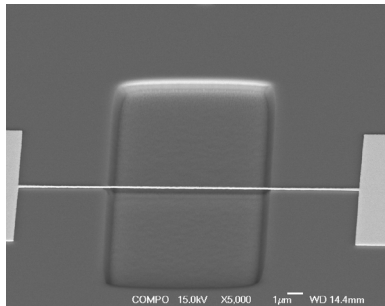
Kunal Lulla, Institut Néel (CNRS), Grenoble

Outline

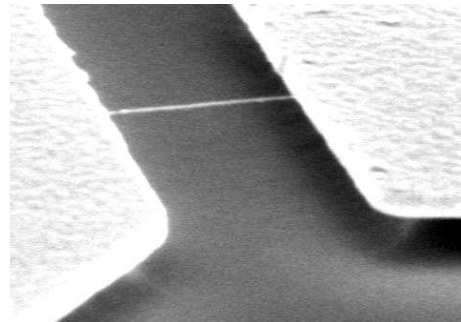
- Introduction to Nanoelectromechanical systems (NEMS)
- Motivation
- Nanomechanics:
 - Nonlinear dynamics of a nanomechanical resonator: **Mode coupling**
- Low Temperature properties (*work in progress*):
 - Mechanical energy dissipation: **Q-factor**
 - Heat transport: **Thermal conductivity**

Introduction

- Mechanical vibrating system with cross-sections $< 1 \mu\text{m}$
 - SHO model
 - extremely low masses $< 10^{-15} \text{ kg}$
 - wide resonant frequency range MHz - GHz
 - materials Si, Si_3N_4 , GaAs, diamond, CNTs, graphene, Al, Au...
- Common geometries: doubly-clamped beams, cantilevers, membranes...

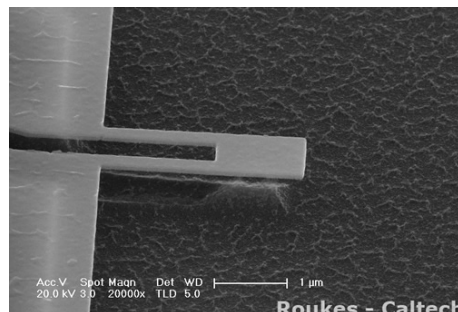


Gold doubly-clamped beam
A Venkatesan *et al*,
Phys. Rev. B **81** 073410 (2010)

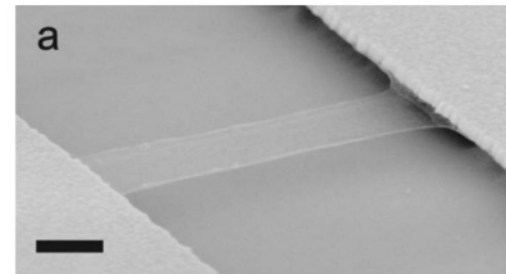


CNT
B. Witkamp thesis, *TU Delft*
(2009)

Silicon carbide cantilever
M Li *et al*,
Nature Nanotechnology
Vol 2 (2007)

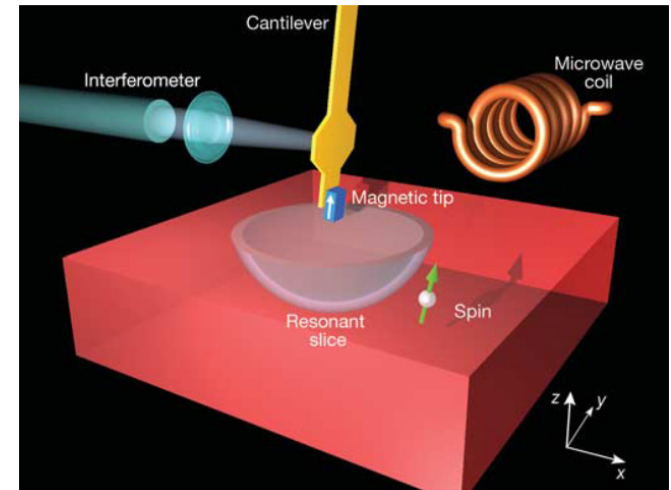
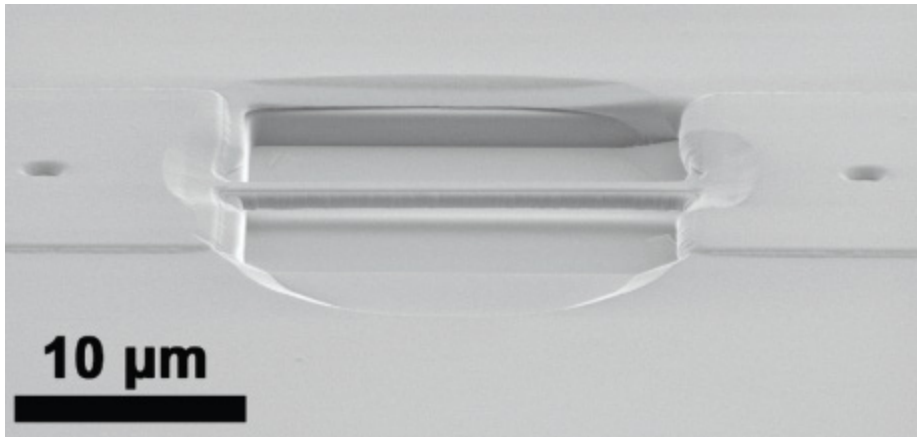


Graphene
A Eichler *et al*,
Nature Nano **Vol 6** (2011)



Motivation (I)

- **Applications of NEMS**
 - Excellent probes for ultrasensitive detection of force, mass, charge etc...

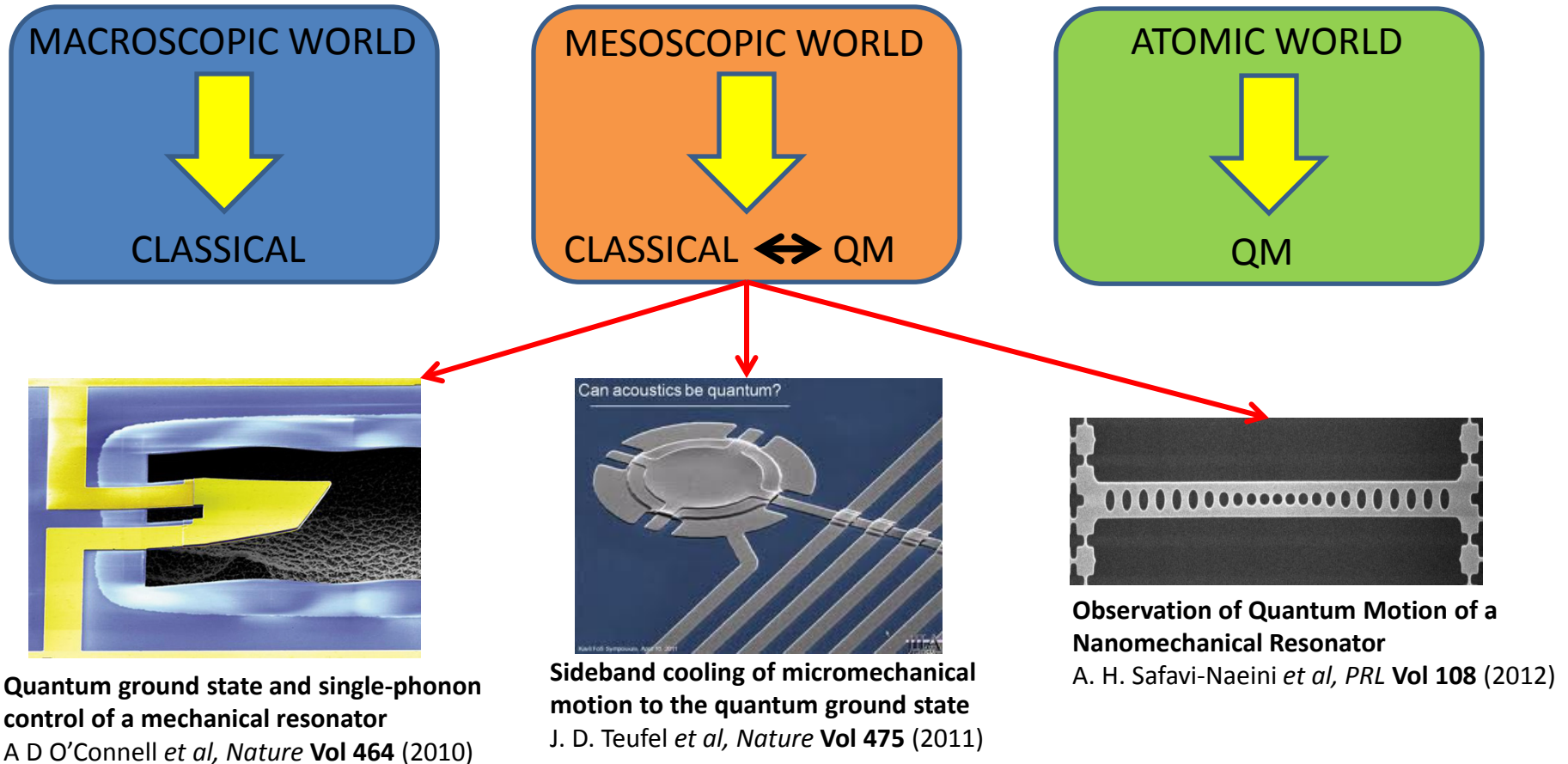


Single spin detection by MR-FM
D Rugar *et al*, *Nature* Vol 430 (2004)

**Fabrication of a Nanomechanical Mass Sensor
Containing a Nanofluidic Channel**
R. A. Barton *et al*, *Nano Letters* Vol 10 (2010)

Need to understand device properties such as **dissipation**, **thermal**, **nonlinear** (**dynamic range**) to improve sensitivities...

Motivation (II)



FOR QM REQUIRE $\hbar\omega > k_B T$

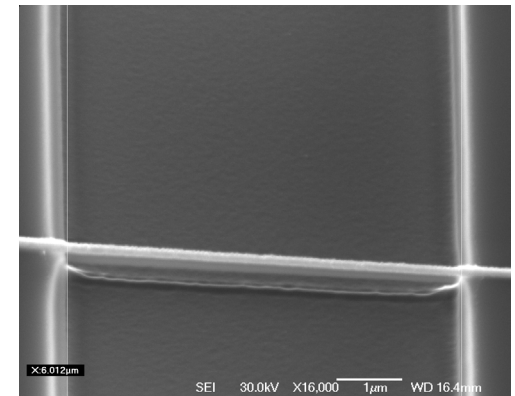
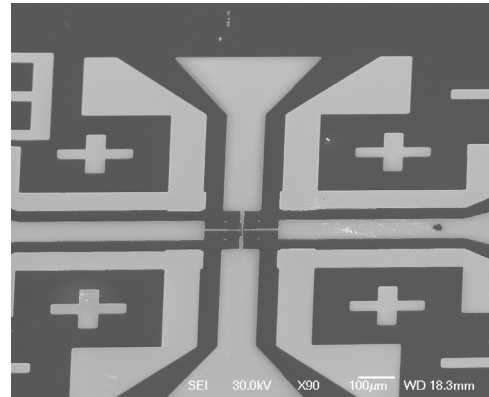
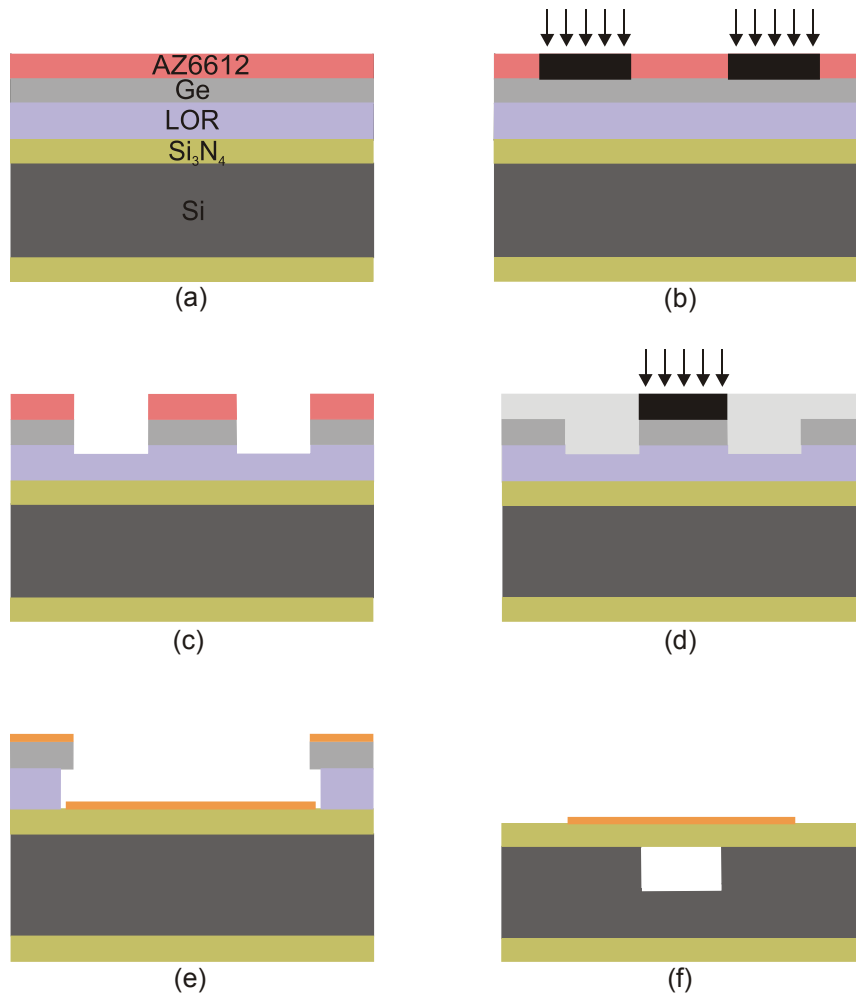
Nanomechanics : Mode Coupling

- (a) Device fabrication
 - (b) Measurement technique
 - (c) Theory
 - (d) Results + Conclusions
- } Mode coupling
+ dissipation
measurements

Device fabrication

Gold-coated silicon nitride beams

Substrate: Si + Si₃N₄ (LPCVD)
HIGHLY STRESSED $\sigma = 1$ GPa !!!



Measurement technique

Magnetomotive

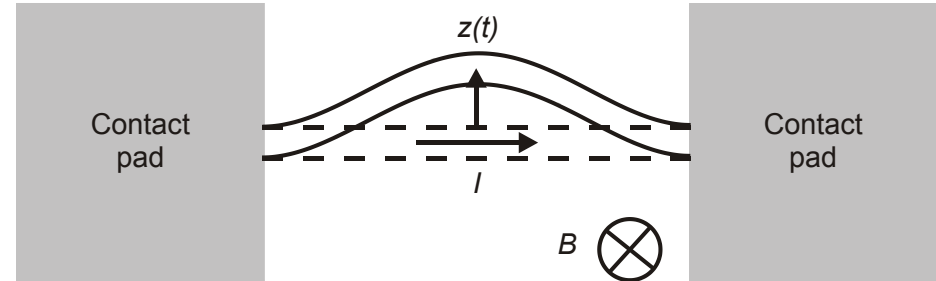
Lorentz force generated perpendicular to both current I and magnetic field B .

Advantages: Simple + use of cryogenic vacuum

Disadvantages: Use of large magnetic fields affects measurement.



Q-factor is loaded by external circuitry (Z_{ext}) and R_e of sample itself



$$Q_L^{-1} = Q_0^{-1} + \beta B^2$$

$$\beta = \frac{l^2}{\omega_0 m} \frac{\Re(Z_{ext})}{|Z_{ext}|^2}$$

Ref : Cleland & Roukes, *Sens & Actuators* **72** , 256 (1999)

Silicon nitride: Low temperature properties

$$f_{0n} = \frac{\pi}{8} (2n + 1)^2 \frac{1}{L^2} \sqrt{\frac{EI}{\rho A}} \sqrt{1 + \frac{0.97 T_0 L^2}{(n + 1)^2 \pi^2 EI}}$$

Length (μm)	Gold thick. (nm)	Mode (n)	f_0 (MHz)	Q_0	
25.5	80	1	5.45	10^6	DISSIPATION
25.5	80	3	16.84	5×10^5	
6.4	80	1	31.36	1×10^5	
4.4	80	1	55.88	6×10^4	
25.5	40	1	7.50	2×10^6	MODE COUPLING
25.5	40	3	22.85	1×10^6	
25.5	40	5	39.28	7×10^5	

Mode coupling: Theory

EOM

$$EI \frac{\partial^4 z}{\partial x^4} - \left[T_0 + \frac{EA}{2L} \int_0^L \left(\frac{\partial z}{\partial x} \right)^2 dx \right] \frac{\partial^2 z}{\partial x^2} + \gamma \frac{\partial z}{\partial t} + \rho A \frac{\partial^2 z}{\partial t^2} = F_L$$

bending
tension
damping
inertial
External force

Only one mode driven at a time:

Mode displacement $z_n(x, t) = u_n(t) g_n(x)$

Mode profile $g_n(x) = c_{1n} \sinh\left(\frac{k_{1n}x}{L}\right) + c_{2n} \cosh\left(\frac{k_{1n}x}{L}\right) + c_{3n} \sin\left(\frac{k_{2n}x}{L}\right) + c_{4n} \cos\left(\frac{k_{2n}x}{L}\right)$

Coefficients $c_1...$ can be found applying boundary conditions for a doubly-clamped beam

$$g_n(0) = g_n(L) = \frac{\partial g}{\partial x}(0) = \frac{\partial g}{\partial x}(L) = 0$$

Ref: K. J. Lulla et al, [arXiv:1204.4487](https://arxiv.org/abs/1204.4487)

Can solve the EOM to obtain equation which is only time dependent

$$\ddot{u}_n + \frac{\omega_{0n}}{Q_n} \dot{u}_n + \omega_{0n}^2 u_n + \lambda I_{nn}^2 u_n^3 = f_n \cos(\omega_n t)$$

Nonlinear coefficient λI_{nn} where:

$$\lambda = \frac{E w^2}{2 \rho L^4} \quad I_{nn} = \int_0^L g'_n(x) g'_n(x) dx$$

Assume a harmonic solution to solve EOM

$$u_n = a_n \cos(\omega_n t) + b_n \sin(\omega_n t)$$

The amplitudes a_n and b_n can be obtained through Fourier analysis

Ref: K. J. Lulla et al, [arXiv:1204.4487](https://arxiv.org/abs/1204.4487)

$$r_n = \sqrt{a^2 + b^2} = \frac{f_n}{\sqrt{\underbrace{\left(\omega_{0n}^2 + \frac{3}{4}\lambda I_{nn}^2 r_n^2 - \omega_n^2\right)^2}_{\text{Duffing nonlinearity}} + \left(\frac{\omega_n \omega_{0n}}{Q_n}\right)^2}}$$

Expanding to lowest order gives

$$f_n^{(1)} = f_{0n} + \frac{3}{32\pi^2 f_{0n}} \lambda I_{nn}^2 r_n^2$$

Key result: Duffing nonlinearity... ‘frequency pulling’

Ref: K. J. Lulla et al, [arXiv:1204.4487](https://arxiv.org/abs/1204.4487)

For mode coupling experiments two modes (**n and m**) of the same beam driven simultaneously therefore

$$F_L = f_n \cos(\omega_n t) + f_m \cos(\omega_m t)$$

Once again solving the EOM gives a dispersion equation very similar to the single mode case

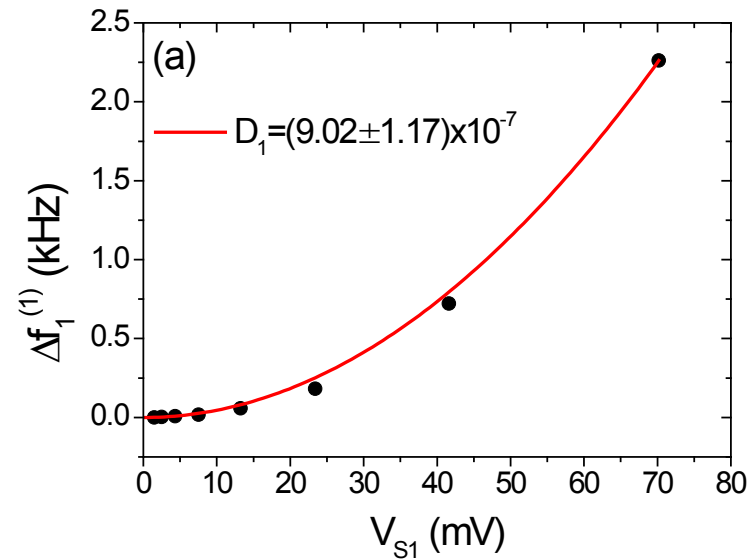
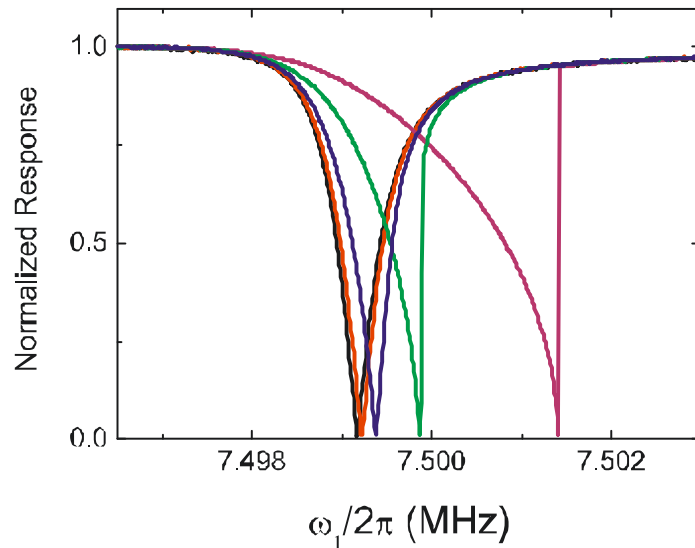
$$f_n^{(2)} = f_n^{(1)} + \frac{1}{8\pi^2 f_n^{(1)}} \lambda \left(\frac{1}{2} I_{nn} I_{mm} + I_{nm} \right) r_m^2$$

Frequency pulling effect, in a similar fashion to duffing type nonlinearity (same source)

Ref: K. J. Lulla et al, [arXiv:1204.4487](https://arxiv.org/abs/1204.4487)

Results: Single mode

Experiments performed @ 100 mK, 3 T

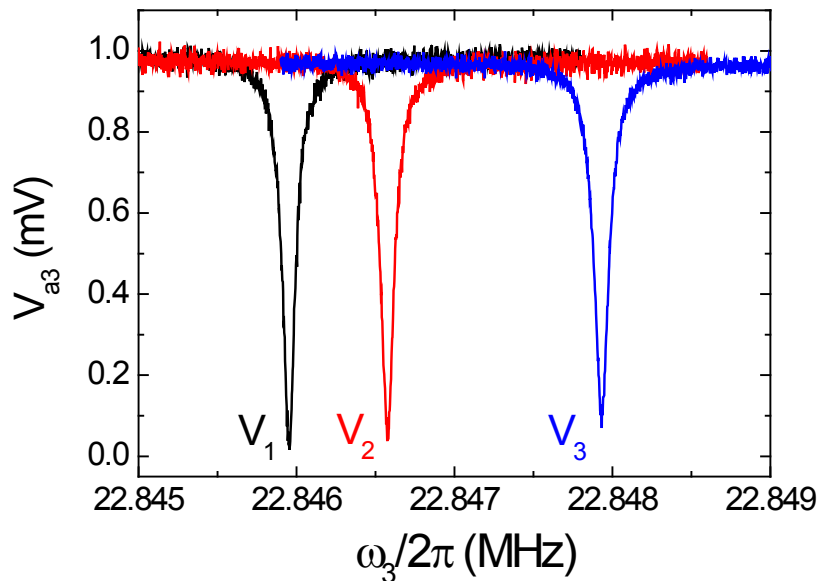


$V_{Sn} = A_n D_n r_n \rightarrow$ Measured voltage related to the actual amplitude of the NEMS via constants A (related to material **Known**) and D (Gain factor in the transmission lines **Unknown**)

Ref: K. J. Lulla et al, [arXiv:1204.4487](https://arxiv.org/abs/1204.4487)

Results: mode coupling

Measured the frequency shift in mode n as a function of the amplitude of mode m .



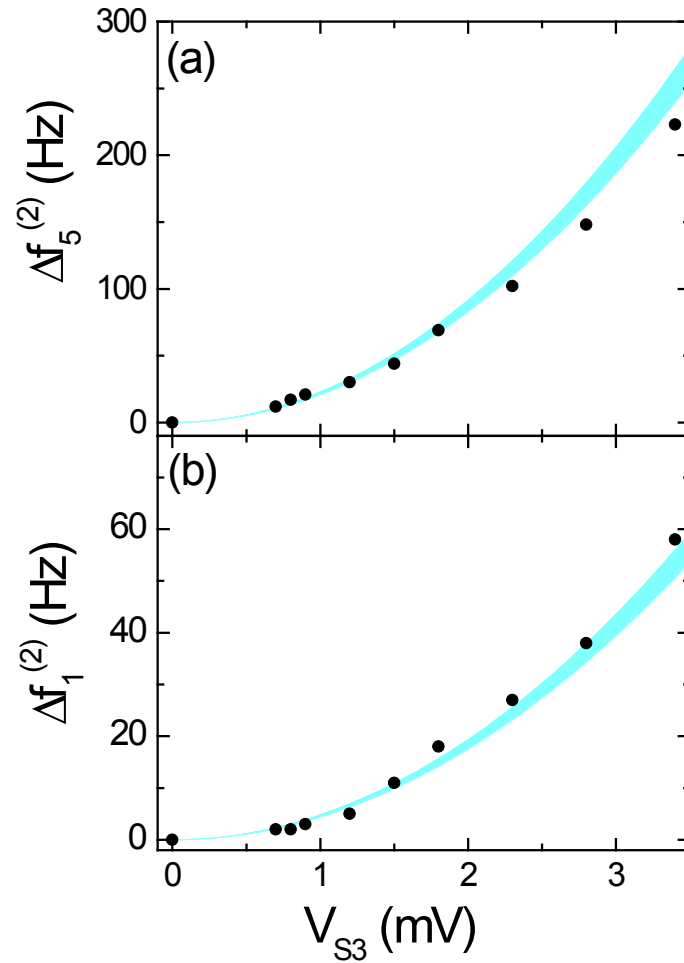
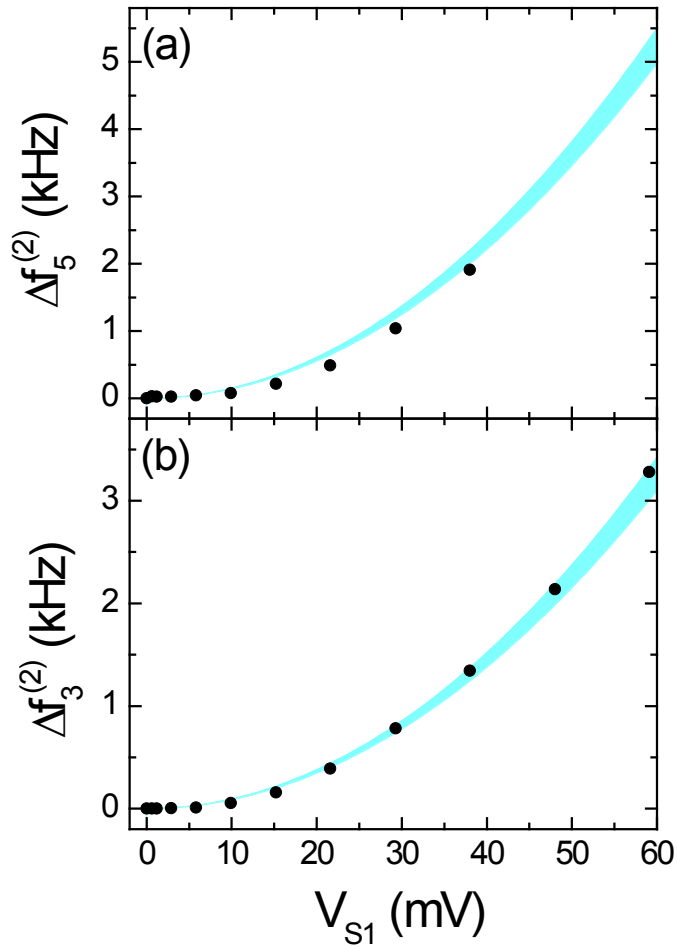
Modes 1 & 3 driven simultaneously:
→ Mode 3 drive kept constant
→ Mode 1 drive increased gradually

f_3 changes with V_{s1} however V_3 does not vary much, neither does its shape, ie. **No energy transfer between modes.**

Sensitivity: 7 Hz / nm

Ref: K. J. Lulla et al, [arXiv:1204.4487](https://arxiv.org/abs/1204.4487)

Results: mode coupling



Ref: K. J. Lulla et al, [arXiv:1204.4487](https://arxiv.org/abs/1204.4487)

Conclusions: mode coupling

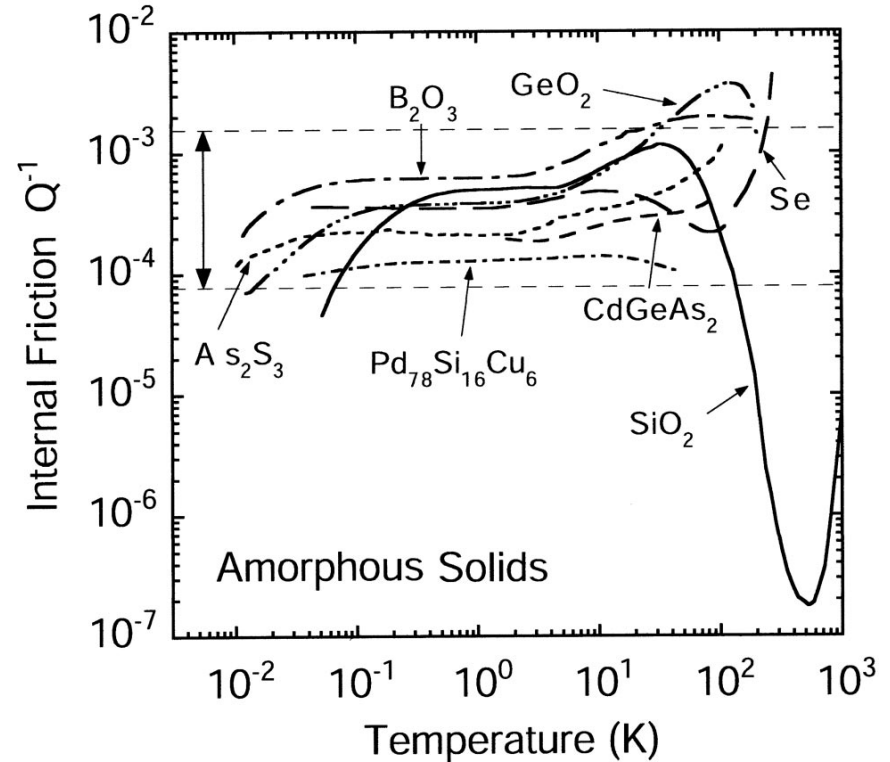
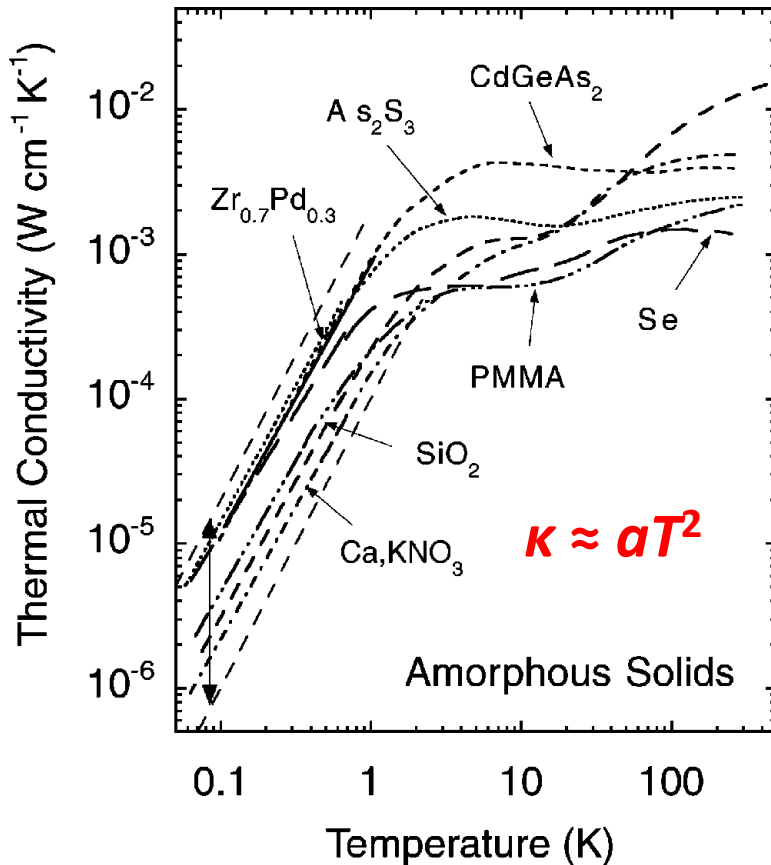
- Good agreement between measurements and theory, coupling between modes is due to the tension induced from the stretching of the beam.
- This inter-modal interaction is very important when describing the mechanical motion of [highly-stressed nanomechanical resonators](#)
- What happens at larger drives, is energy transfer between the different modes possible?
- Improve sensitivity by measuring resonators with even larger quality factors?

Ref: K. J. Lulla et al, [arXiv:1204.4487](#)

Dissipative and thermal properties at low temperatures

- (a) Previous work (experimental + theoretical)
- (b) Dissipation in silicon nitride
- (c) Thermal conductivity in silicon nitride (measurement technique + results)
- (d) Discussion

Previous work: Bulk systems



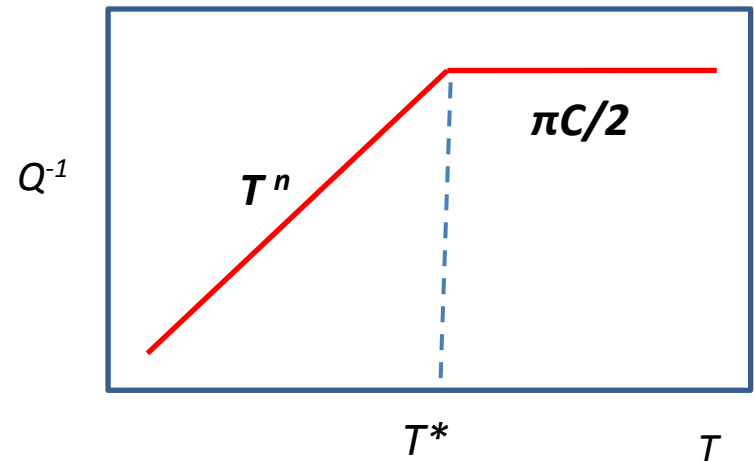
Universal behaviour $\rightarrow$ Glassy range

Ref: R. O. Pohl et al, Low temperature thermal conductivity and acoustic attenuation in amorphous solids. *Rev. Mod. Phys.* **74** (2002)

Standard Tunnelling Model

Two-level systems (TLS) with broad distribution of energies E and relaxation times $\tau \rightarrow$ **Anharmonic oscillations**

TLS $\leftrightarrow$ electron/phonon interaction



Thermal conductivity
(phonons):

$$\kappa(T) = \frac{\rho k_b^3}{6\pi\hbar^2} \frac{v}{P\gamma} T^2$$

Interaction	Q_0^{-1}
Resonant	Negligible when $\hbar\omega \ll k_B T$
Relaxation	aCT^n/ω ($\omega\tau_{min} \gg 1$) $\pi C/2$ ($\omega\tau_{min} \ll 1$)

$n = 3$ (phonons), 1 (electrons) C – Coupling strength

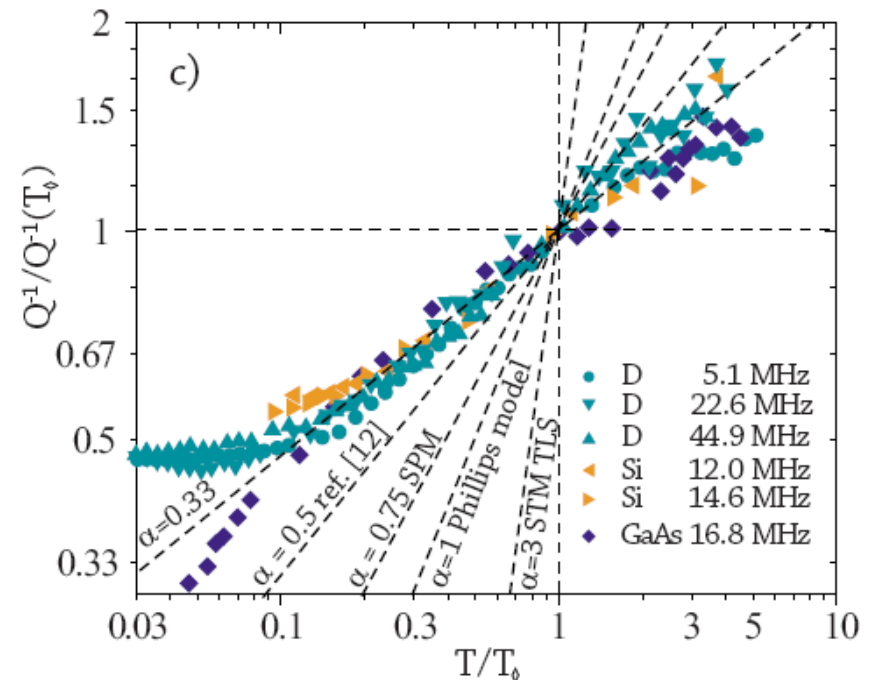
Previous work: Mesoscopic systems

Thermal conductance of silicon nanowires follows T^3 dependence as predicted by the Debye model for perfect crystals.

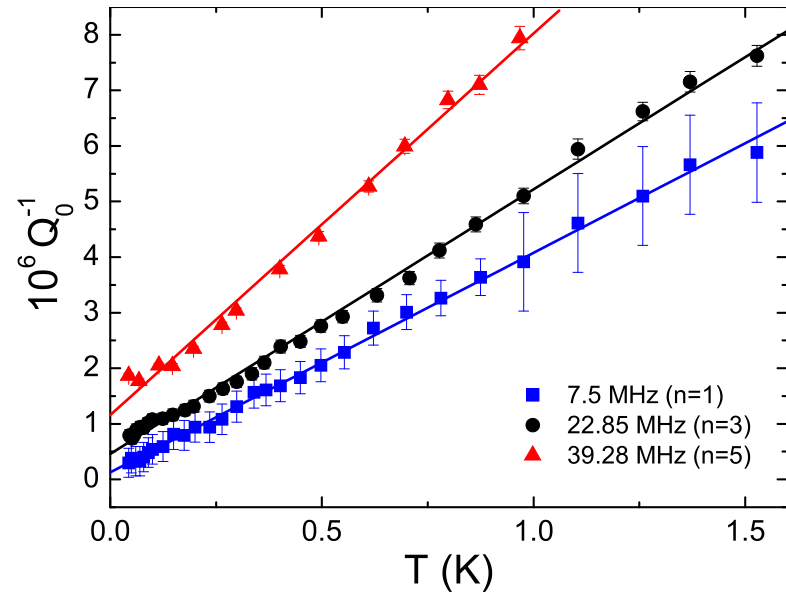
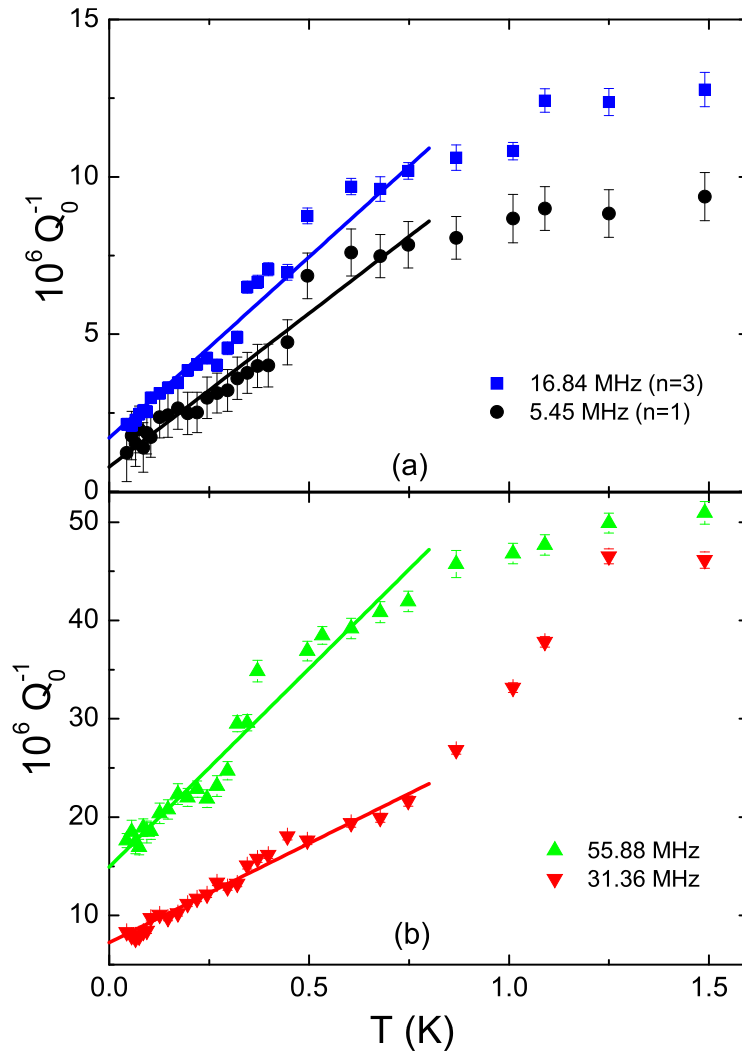
→ O. Bougeois et al., *JAP* **101**, 014104 (2007)

Dissipation measurements in various materials seems to show the same behaviour ... Universal signature in the dissipation in NEMS ?

→ M. Imboden and P. Mohanty, *PRB* **79**, 125424 (2009)



Dissipation vs Temperature

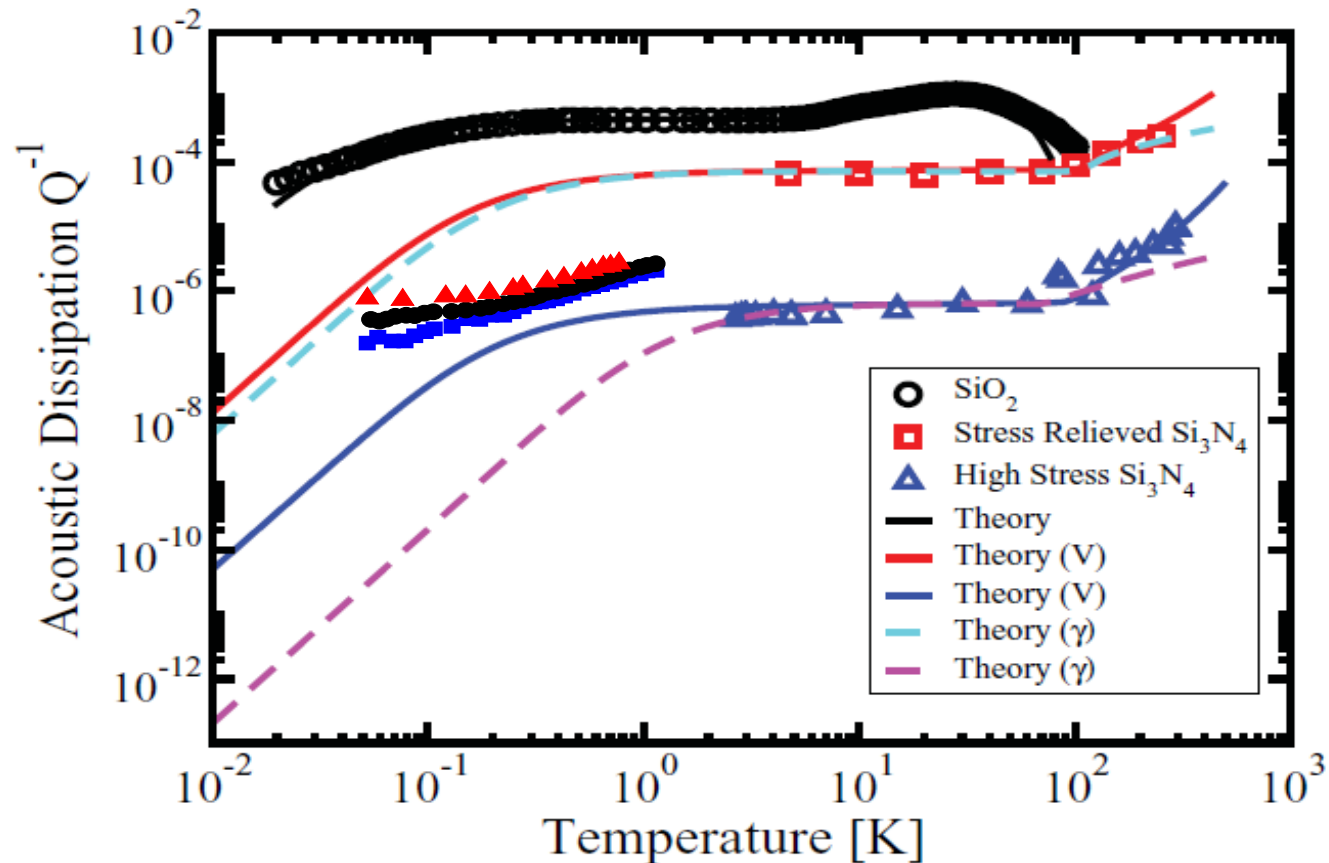


Straight lines correspond to the power law T^n where $n=1$

SiN + Al: $Q_0^{-1} \sim T$ ($T < 600$ mK)

Ref: T. Rocheleau et al., *Nature* **463**, 7 (2010)

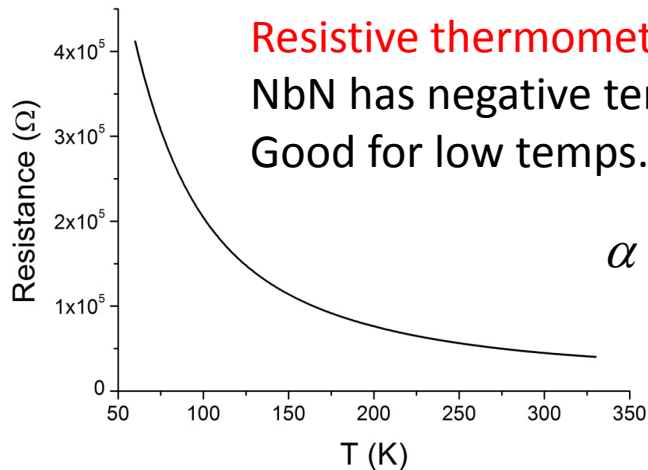
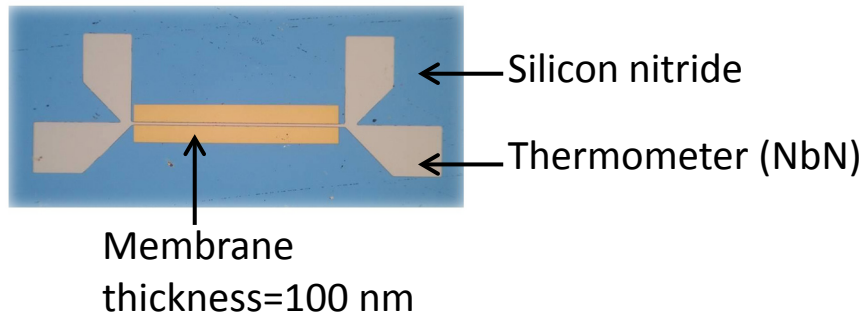
Dissipation: Comparison to theory



Ref: J. Wu and C. C. Yu, *How stress can reduce dissipation in glasses*, *PRB*, vol. 84, 174109 (2011).

Thermal measurements: Devices

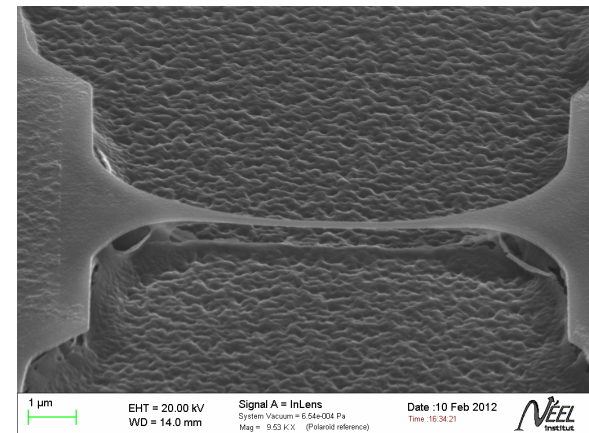
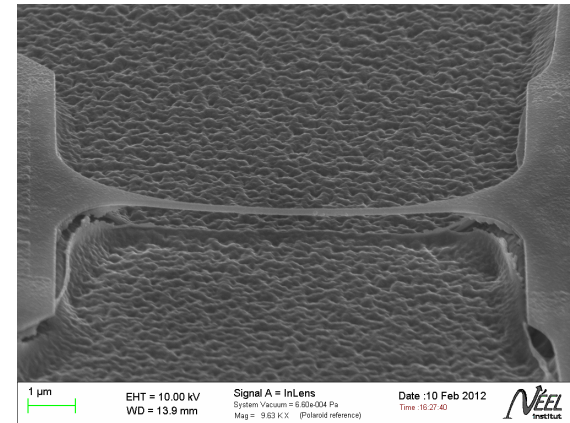
Membranes



Resistive thermometry:
NbN has negative temp. Coeff.
Good for low temps.

$$\alpha = -\frac{1}{R} \frac{dR}{dT}$$

Doubly clamped beams



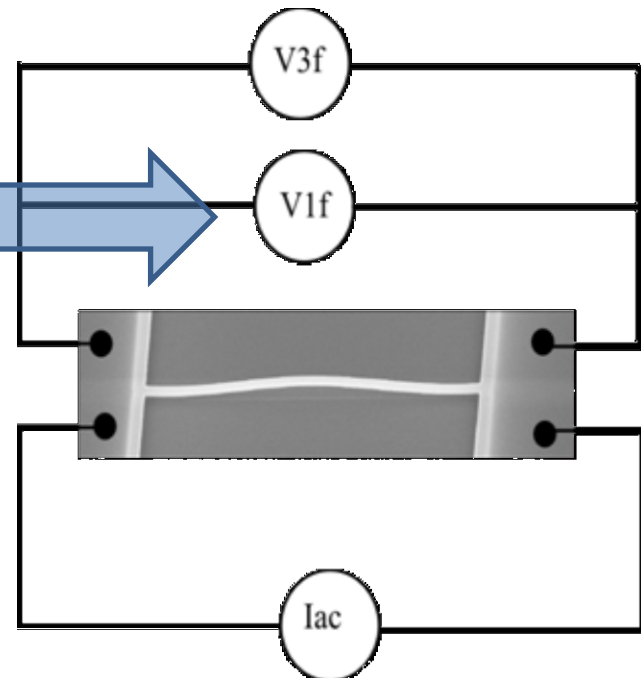
Thermal Measurements: technique

The 3 ω method

- Ac current passed through NbN transducer : $I_{ac} = A \sin(\omega t)$
- Generate oscillating T proportional to power dissipated : $I_{ac}^2 \rightarrow 2\omega$
- Resistance proportional to temperature $\rightarrow 2\omega$
- $V_{3\omega} = I_{ac}R \rightarrow 3\omega$ (at low freq $\rightarrow K$)

Disadvantage:

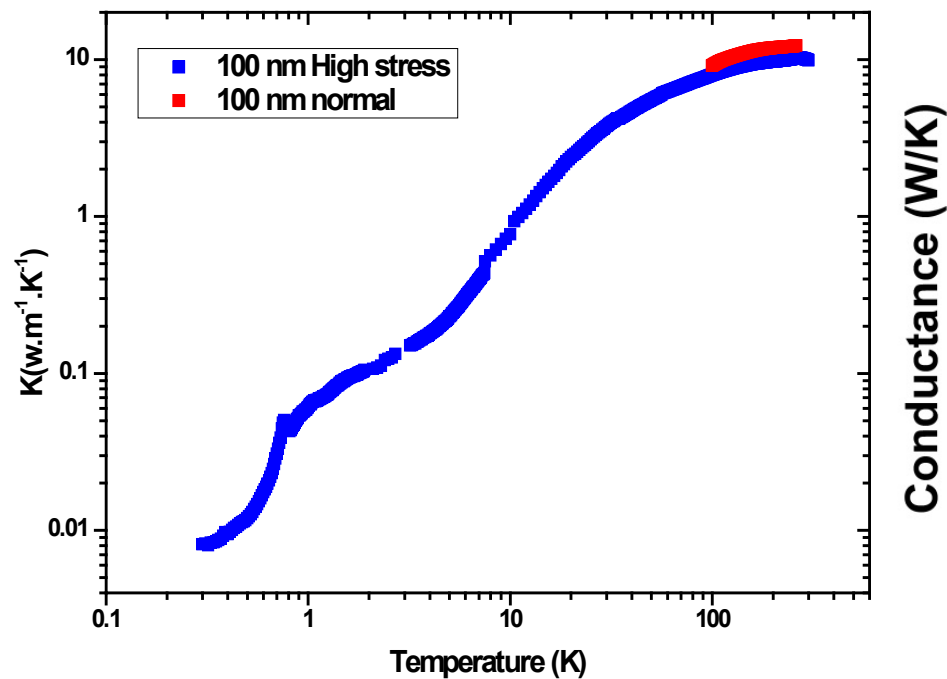
Large signal at ω however it can be filtered out using a Wheatstone bridge for example



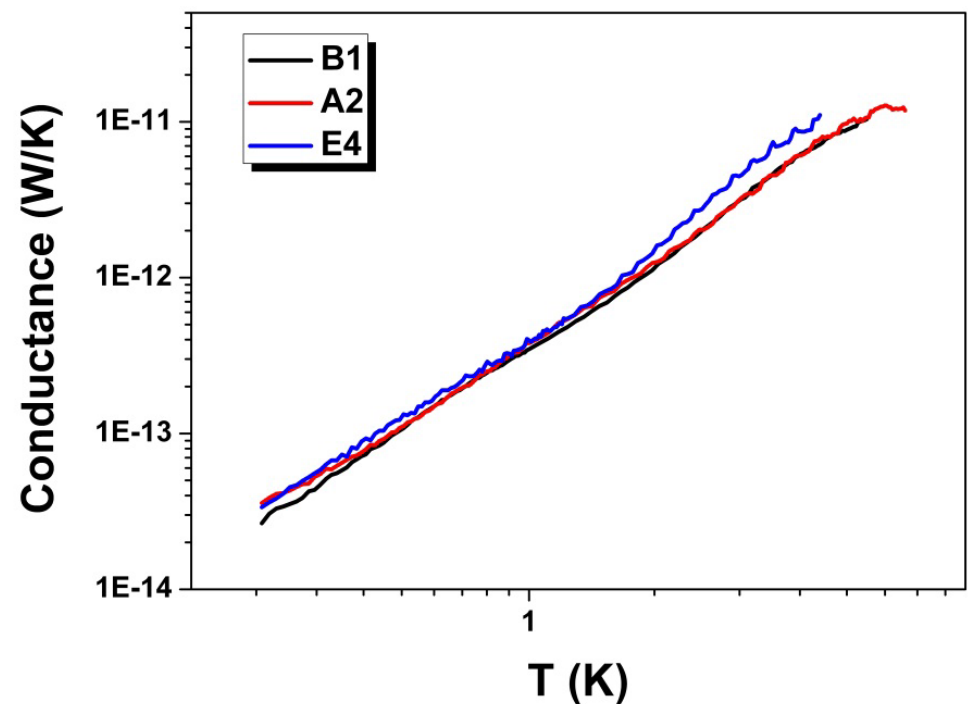
Ref: N. O. Birge and S. R. Nagel, Rev. Sci. Instrum. **58**, 1464 (1987)
L. Lu, W. Yi and D. L. Zhang, Rev. Sci. Instrum. **72**, 2996 (2001)

Thermal measurements: Results

Membranes



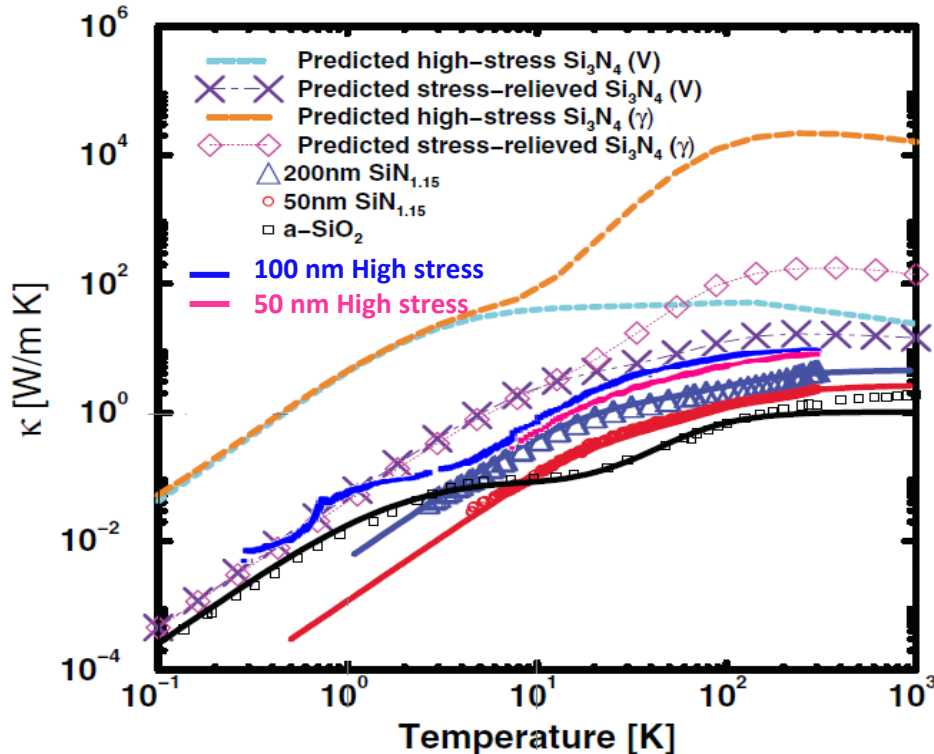
Beams



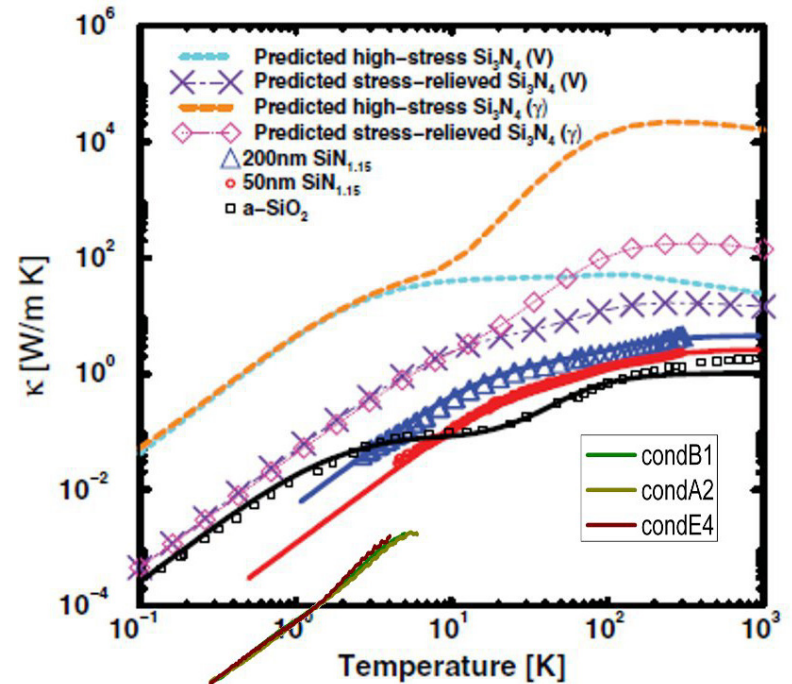
- For both structures $K \approx aT^2$

Thermal conductivity: Comparison to theory

Membranes



Beams



Ref: J. Wu and C. C. Yu, *How stress can reduce dissipation in glasses*, *PRB*, vol. 84, 174109 (2011).

Conclusions

DISSIPATION

- $n = 1$, STM indicates TLS-electron interaction (electrons in the gold layer??)
→ Previous measurements on gold resonators revealed a $T^{0.5}$
- Some features are reminiscent of TLS dominated dissipation however no quantitative agreement with theory
- The finite value of $Q_0^{-1}(0)$ = clamping loss?

THERMAL CONDUCTIVITY

- Preliminary results show that the thermal conductance varies as T^2 however it depends on size + geometry.
- Characteristic physical length scales play a key role
 1. Phonon mean free path (phonon transport ballistic or not?)
 2. Dominant phonon wavelength (a few hundreds of nm below 1K)

Summary + Future work

- Highly stressed silicon nitride leads to higher resonance frequencies and much larger Q-factors than other NEMS of similar dimensions.
- **Mode coupling:** We understand! (At least in the regime we have studied)
- **Thermal measurements + dissipation :** We do not understand!
- Keep measuring !!
- Measure low stress nitride samples to quantify the effect of the stress
- Come up with a theory which unifies TLS, dimensionality and stress

Acknowledgements

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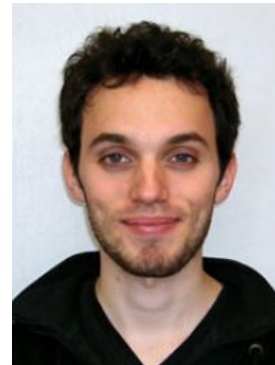
Grenoble



Dr. E. Collin



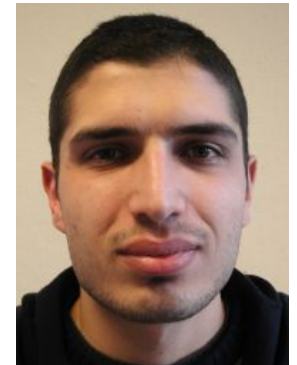
Dr. O. Bourgeois



M. Defoort



C. Blanc



H. Ftouni

Thank you !

3- ω method + wheatstone bridge set-up

